

This Page Is Inserted by IFW Operations
and is not a part of the Official Record

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

IMAGES ARE BEST AVAILABLE COPY.

**As rescanning documents *will not* correct images,
please do not report the images to the
Image Problem Mailbox.**

FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office

Atty.
Dkt. No.

M#

Client Ref.

0273961

P-0153.010-US

INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

Applicant: FINDERS et al.

Appln. No.: 09/671,802

Filing Date: September 28, 2000

Examiner: Chacko Davis

Group Art Unit: 1756

Date: April 9, 2003

1

of

1

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR						
BR						
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

GROUP 1700
APR 15 2003
RECEIVED

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
						Enclosed	No	Enclose	No
WO	OR	WO 98/28665	07/1998	PCT	LOOPSTRA et al.				
WO	PR	WO 98/40791	09/1998	PCT	LOOPSTRA et al.				
WO	QR	WO 97/33205	09/1997	PCT	VAN DER WERF et al.				
WO	RR	EP 0 687 956 A1	05/1995	EPO	WANGLER et al.		X		X
	SR								
	TR								
	UR								

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

VR									
WR									
XR									
YR									
ZR									
AAR									

Examiner

Chacko Davis

Date Considered:

04/30/2003

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

Atty.
Dkt. No.

M#

Client Ref.

0273961

P-0153.010 US

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**



Applicant: FINDERS et al.

Appln. No.: 09/671,802

Filing Date: September 28, 2000

Date: March 28, 2003

Page

1

of

4

Examiner: Chacko Davis

Group Art Unit: 1756

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
WD	AR	3,639,039	02/1972	RHODES, JR.	350	162SF	---
WD	BR	3,658,420	04/1972	AXELROD	356	71	---
WD	CR	3,492,635	01/1970	FARR	340	15.5	---
WD	DR	3,729,252	04/1973	NELSON	350	162	---
WD	ER	3,776,633	12/1973	FROSCH et al.	353	132	---
WD	FR	4,370,026	01/1983	DUBROEUCQ et al.	350	163	---
WD	GR	4,472,023	09/1984	YAMAMOTO	350	162.11	---
WD	HR	4,497,015	01/1985	KONNO et al.	362	248	---
WD	IR	4,619,508	10/1986	SHIBUYA et al.	353	1,225D	---
WD	JR	4,780,747	10/1988	SUZUKI et al.	355	683	---
WD	KR	4,789,222	12/1988	OTA et al.	350	162.7	---
WD	LR	4,814,829	03/1989	KOSUGI et al.	355	43	---
WD	MR	4,841,341	06/1989	OGAWA et al.	355	43	---
WD	NR	4,851,882	07/1989	TAKAHASHI et al.	355	46	---
WD	OR	4,854,669	08/1989	BIRNBACH et al.	350	162.12	---
WD	PR	4,939,630	07/1990	KIKUCHI et al.	362	268	---
WD	QR	4,947,413	08/1990	JEWELL et al.	378	34	---
WD	RR	4,970,546	11/1990	SUZUKI et al.	355	53	---
WD	SR	5,004,348	04/1991	MAGOME	356	401	---
WD	TR	5,153,773	10/1992	MURAKI et al.	359	619	---
WD	UR	5,191,374	03/1993	HAZAMA et al.	355	43	---
WD	VR	5,337,097	08/1994	SUZUKI et al.	353	101	---

FOREIGN PATENT DOCUMENTS

Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
WR				Enclosed	No

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

XR					
YR					
ZR					

Examiner Deborah Chacko Davis

Date Considered: 04/30/2003

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

Atty.
Dkt. No.

M#

Client Ref.

0273961

P-0753.010-US

INFORMATION DISCLOSURE STATEMENT
BY APPLICANT



Applicant: FINDERS et al.

Appln. No.: 09/671,802

Filing Date: September 28, 2000

Date: March 28, 2003

Page

2

of

4

Examiner: Chacko Davis

Group Art Unit: 1756

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
<i>WLD</i>	AR	6,084,655	07/2000	SUZUKI et al.	355	53	—
<i>WLD</i>	BR	6,128,068	10/2000	SUZUKI et al.	355	53	—
<i>WLD</i>	CR	6,271,909	08/2001	SUZUKI et al.	355	53	—
<i>WLD</i>	DR	2001/0007495	07/2001	SUZUKI et al.	355	53	—
<i>WLD</i>	ER	2001/0015797	08/2001	SUZUKI et al.	355	53	—
<i>WLD</i>	FR	6,252,647	06/2001	SHIRAISHI	355	53	—
<i>WLD</i>	GR	6,211,944	04/2001	SHIRAISHI	355	53	—
<i>WLD</i>	HR	6,233,041	05/2001	SHIRAISHI	355	53	—
<i>WLD</i>	IR	6,016,187	01/2000	NOGUCHI et al.	355	53	—
<i>WLD</i>	JR	5,742,376	04/1998	MAKINOCHI	355	53	—
<i>WLD</i>	KR	5,675,401	10/1997	WANGLER et al.	355	67	—
<i>WLD</i>	LR	5,712,698	01/1998	POSCHENRIEDER	355	46	—
<i>WLD</i>	MR	5,517,279	05/1996	HUGLE et al.	355	46	—
<i>WLD</i>	NR	5,659,409	08/1997	OOI et al.	349	10	—
<i>WLD</i>	OR	6,285,443	09/2001	WANGLER et al.	355	67	—
<i>WLD</i>	PR	6,259,512	07/2001	MIZOUCHI	355	67	—
<i>WLD</i>	QR	6,285,855	09/2001	TSUJI	399	618	—
<i>WLD</i>	RR	4,988,188	01/1991	OHTA	353	122	—
<i>WLD</i>	SR	6,049,374	01/2000	KOMATSUDA	355	67	—

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
					Enclosed	No
	TR					
	UR					
	VR					

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

	WR					
	XR					
	YR					
	ZR					
	AAR					
	BBR					

Examiner

Chacko Davis

Date Considered: 04/30/2003

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

Atty.
Dkt. No.

M#

Client Ref.

273961

P-0753.010-US

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**



Date: March 28, 2003

Page

3

of

4

Applicant: FINDERS et al.

Appln. No.: 09/671,802

Filing Date: September 28, 2000

Examiner: Chacko Davis

Group Art Unit: 1756

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
ND	AR 4,931,830	06/1990	SUWA et al.	355	71	
ND	BR 4,241,389	12/1980	HEIMER	362	297	
ND	CR 3,770,340	11/1973	CRONIN et al.	350	162	
ND	DR 4,291,938	09/1981	WAGNER	350	91	
ND	ER 4,936,665	06/1990	WHITNEY	350	451	

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
ND	FR WO 92/03842	03/1992	PCT	Shiraishi .	X		X	
ND	GR 61-91662 (A)	05/1986	Japan	Horiuchi	X		X	
ND	HR 0 011 709 A2	10/1979	European	Wagner		X		X
ND	IR EP0 747772 A1	04/1996	European	Wangler et al.		X		X
	JR							

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

ND	KR	Revocation of EP-B-0500393 to Canon Kabushiki Kaisha - May 26, 2000						
ND	LR	Cronin et al., "Dynamic Coherent Optical System," Optical Engineering, Mar/Apr 1973, Vol. 12, No. 2, pp. 50-55.						
ND	MR	Reynolds, "A concept for a High Resolution Optical Lithographic System for Producing One-Half Micron Linewidths," Optical Microlithography V (1986) SPIE Vol. 633, pp. 228-238.						
ND	NR	Yang et al, "Effect of central obscuration on image formation in projection lithography," SPIE Vol. 1264 Optical/Laser Microlithography III (1990), pp. 477-485.						
ND	OR	Pol et al., "Excimer laser based lithography: a deep-ultraviolet wafer stepper for VLSI processing," Optical Engineering, April 1987, Vol. 26, No. 4, pp. 311-318.						
ND	PR	Berry, "Pattern recognition automatic fine alignment," reprinted from Optical Microlithography - Technology for the Mid-1980s, Proc. SPIE Vo. 334, pp. 10-16 (1982)						
ND	QR	Fehrs et al, "Illuminator Modification of an Optical Aligner," KTI Microelectronics Seminar, Proceedings, Nov. 6-7, 1989, San Diego, CA. pp. 217-230.						

Examiner

D. J. Chacko Davis

Date Considered:

04/30/2003

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office

Atty.
Dkt. No.

M#

Client Ref.

0273961

P-0153.010-US

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**



Applicant: FINDERS et al.

Appln. No.: 09/671,802

Filing Date: September 28, 2000

Date: March 28, 2003

Page

4

of

4

Examiner: Chacko Davis

Group Art Unit: 1756

U.S. PATENT DOCUMENTS:

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
<i>MD</i>	AR	5,598,250	01/1997	BAE	355	67	—
<i>MD</i>	BR	6,452,662 B1	09/2002	MULKENS et al.	355	67	—
	CR						
	DR						
	ER						
	FR						
	GR						
	HR						
	IR						
	JR						
	KR						
	LR						
	MR						
	NR						

RECEIVED
MAR 31 2003
TC 1700

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name		Abstract		Readily Available	
							Enclosed	No	Enclose	No
MD	OR	0 564 264 A1	10/1993	EPO	Shiozawa et al.		X		X	
MD	PR	DE 4421053 A1	12/1995	Germany	Wangler			X		X
MD	QR	EP 0794 462A2	09/1997	EPO	Poschenrieder et al.		X		X	
	RR									
	SR									
	TR									
	UR									

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

<i>MD</i>	VR	Taiwanese Patent Office Search Report re: Taiwan patent Appl. No. 88105528 dated February 11, 2000			
<i>MD</i>	WR	European Search Report re: EP 99 302613, dated July 13, 2001			
	XR				
	YR				
	ZR				
	AAR				

Examiner

Deborah L. Davis

Date Considered:

04/30/2003

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.